

<b>Notice of References Cited</b>	Application/Control No. 10/621,264		Applicant(s)/Patent Under Reexamination HAYAISHI, IKUO	
	Examiner CHRISS S. YODER III		Art Unit 2622	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,739,924 A	04-1998	Sano, Homare	358/487
*	B	US-7,359,571 B2	04-2008	Terashita, Takaaki	382/274
*	C	US-5,016,039	05-1991	Sosa et al.	396/50
*	D	US-6,493,468 B1	12-2002	Matsuura, Takahiro	382/274
*	E	US-5,617,141 A	04-1997	Nishimura et al.	348/366
*	F	US-7,262,798 B2	08-2007	Stavely et al.	348/255
*	G	US-2004/0239963 A1	12-2004	Terashita, Takaaki	358/001.9
*	H	US-5,550,587 A	08-1996	Miyadera, Shunichi	348/223.1
*	I	US-6,011,547 A	01-2000	Shiota et al.	382/254
*	J	US-5,808,681 A	09-1998	Kitajima, Tatsutoshi	348/371
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.